

# 簡介 - MOSFET

- ❖ MOSFET INTRODUCTION
- ❖ DC PARAMETER
- ❖ AC PARAMETER
- ❖ POWER RELATED
- ❖ DATA SHEET EXAMPLE

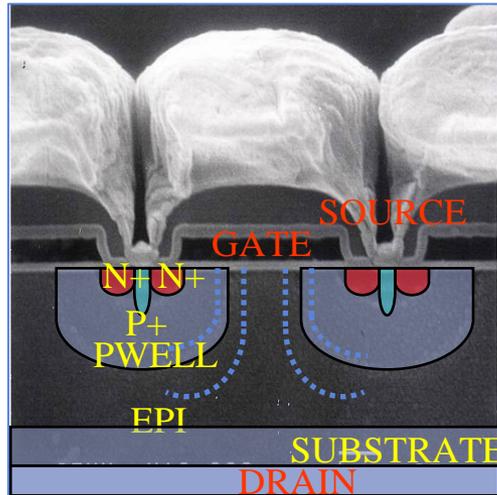
CET CONFIDENTIAL

CHINO-EXCEL TECHNOLOGY

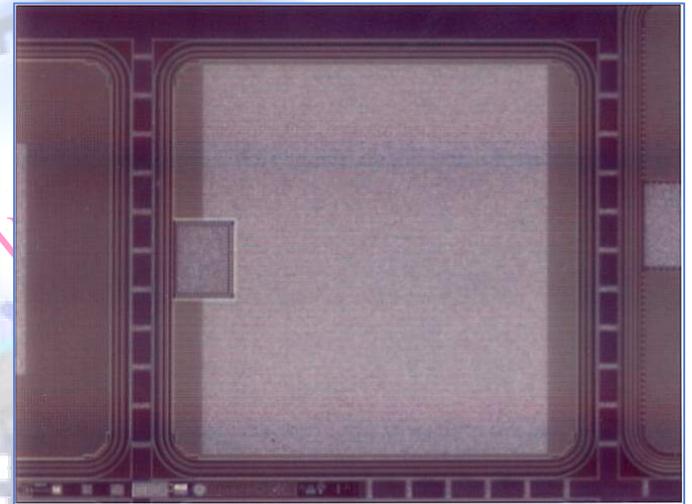
CHINO EXCEL TECHNOLOGY



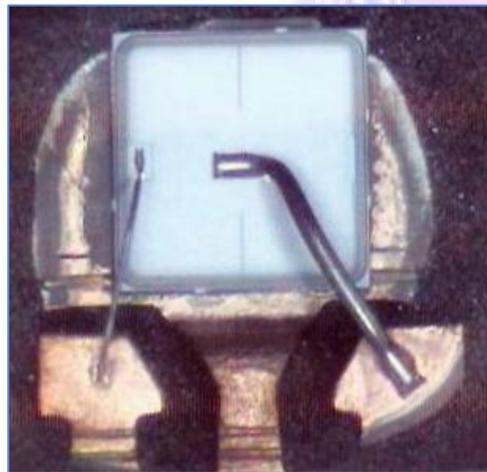
# MOSFET INTRODUCTION



UNIT CELL SEM



TOP-VIEW



WIRE BOND

# MOSFET 參數特性-DC PARAMETER

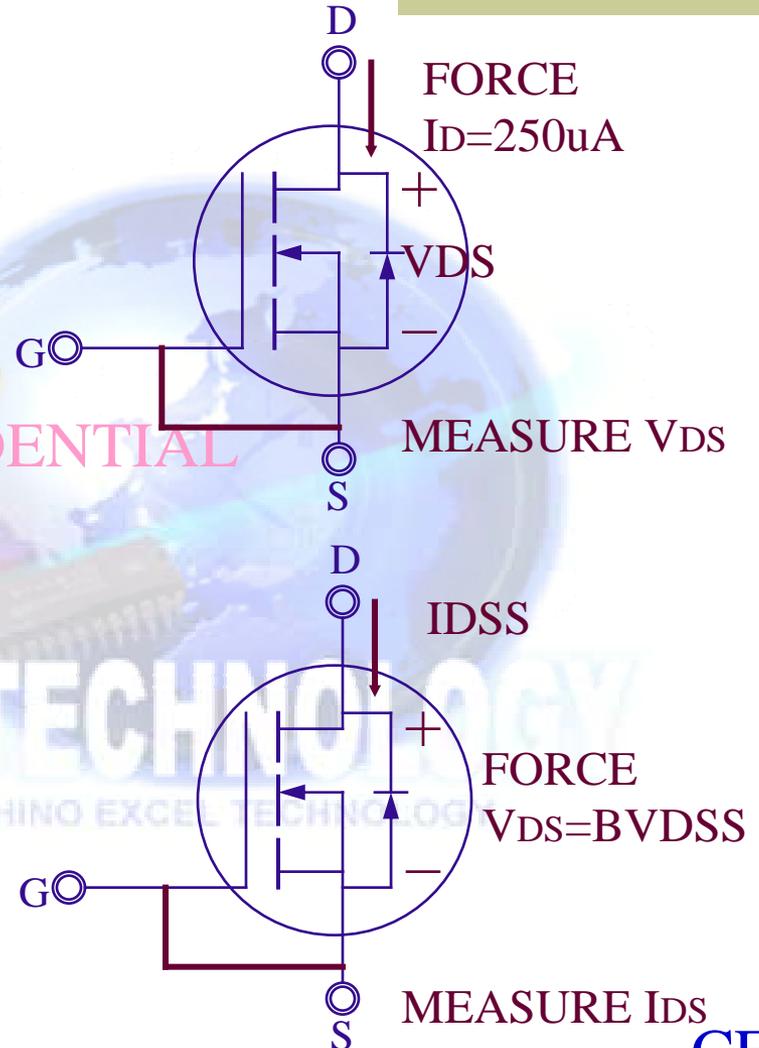
## ❖ DC PARAMETER

- BVDSS ( $V_{DS}$ ) & LEAKAGE( $I_{DSS}$ )
- BVGSS ( $V_{GS}$ ) & LEAKAGE( $I_{GSS}$ )
- ON-RESISTANCE( $R_{DSON}$ )
- THRESHOLD VOLTAGE ( $V_{GS}(TH)$ )
- FORWARD TRANSCONDUCTANCE ( $G_{FS}$ )
- DIODE FORWARD VOLTAGE ( $V_{FSD}$ )

## DC PARAMETER-BVDSS/IDSS

**BVDSS:**此為Drain端 – Source端所能承受電壓值，主要受制內藏逆向二極體的耐壓，其測試條件為  $V_{GS}=0V$ ， $I_D=250\ \mu A$ 。該特性與溫度成正比。

**IDSS:**即所謂的洩漏電流，通常很小，但是有時為了確保耐壓，在晶片周圍的設計，多少會有洩漏電流成分存在，此最大可能達到標準值10倍以上。該特性與溫度成正比。

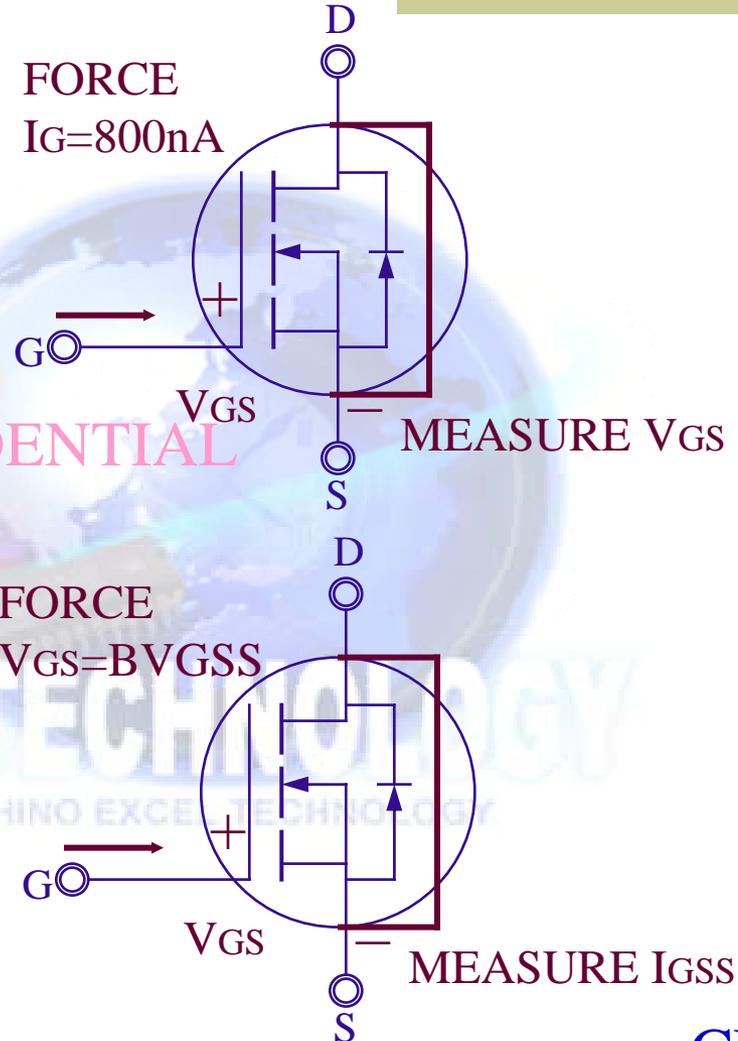


CET CONFIDENTIAL

## DC PARAMETER-BVGSS/IGSS

**BVGSS:**此為GATE端 – Source端的絕緣層所能承受電壓值，主要受制閘極氧化層的耐壓,其測試條件為  $V_{DS}=0V$ ， $I_{SGS}=800\text{ nA}$ 。該特性與溫度無關。

**IGSS:**此為在閘極周圍所介入的氧化膜的洩極電流，此值愈小愈好，標準值約為 $10\text{ nA}$ 。當所加入的電壓，超過氧化膜的耐壓能力時，往往會使元件遭受破壞。

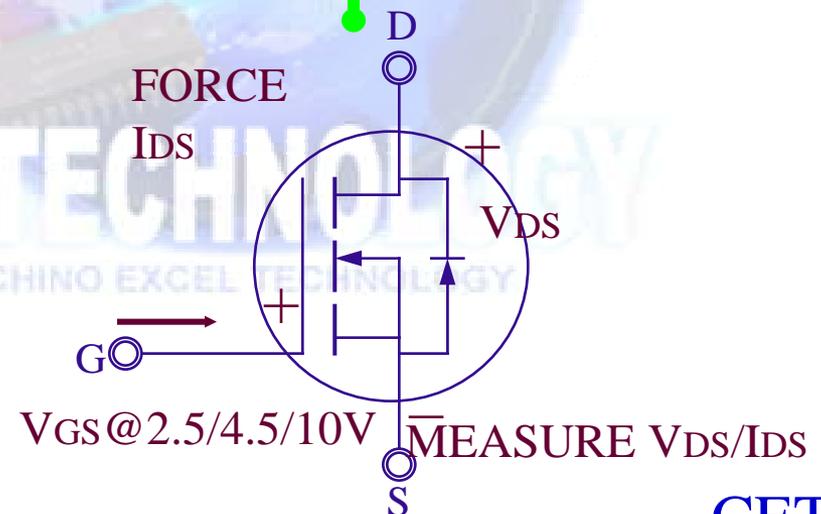
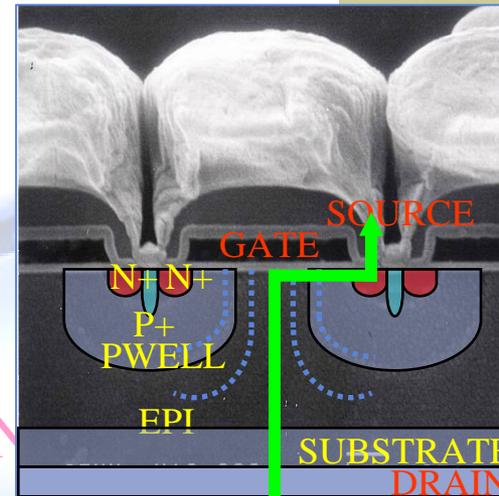


## DC PARAMETER-RDSON

**RDSON:導通電阻值 (ON-RESISTANCE)**  
低壓POWER MOSFET最受矚目之參數

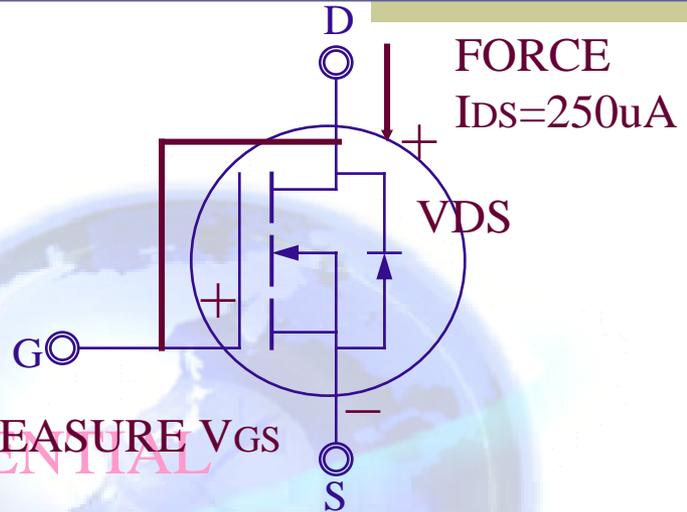
$$R_{DS(on)} = R_{SOURCE} + R_{CHANNEL} + R_{ACCUMULATION} + R_{JFET} + R_{DRIFT(EPI)} + R_{SUBSTRATE}$$

低壓POWER MOSFET 導通電阻是由不同區域的電阻所組成，大部分存在於  $R_{CHANNEL}$ ， $R_{JFET}$  及  $R_{EPI}$ ，在高壓MOS則集中於  $R_{EPI}$ 。為了降低導通電阻值，MOSFET晶片技術上朝高集積度邁進，在製程演進上，TRENCH DMOS以其較高的集積密度，逐漸取代PLANAR DMOS成爲MOSFET製程技術主流。該特性與溫度成正比。

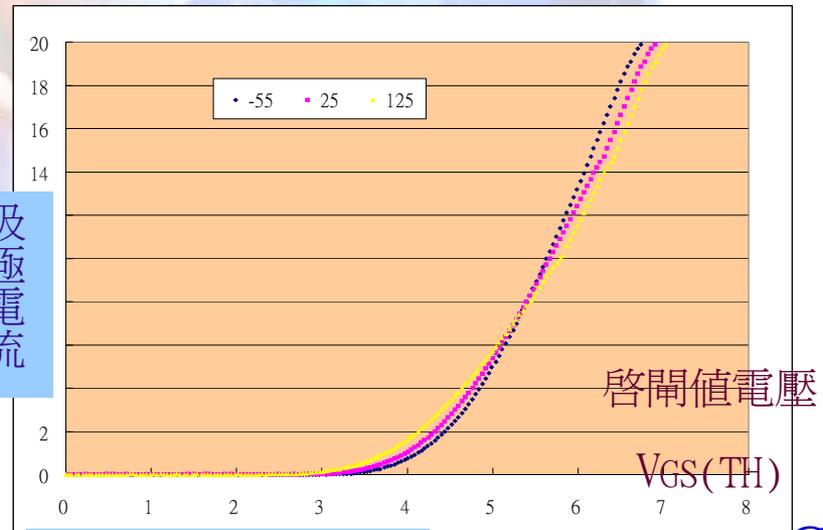


## DC PARAMETER-V<sub>TH</sub>

V<sub>TH</sub>:使 POWER MOS 開始導通的輸入電壓稱 THRESHOLD VOLTAGE。由於電壓在V<sub>GS(TH)</sub>以下，POWER MOS 處於截止狀態，因此，V<sub>GS(TH)</sub>也可以看成耐雜訊能力的一項參數。V<sub>GS(TH)</sub>愈高，代表耐雜訊能力愈強，但是，如此要使元件完全導通，所需要的電壓也會增大，必須做適當的調整，一般約為 2~4V，與 BJT 導通電壓 V<sub>BE</sub>=0.6V比較，其耐雜訊能力相當良好。該特性與溫度成反比。



汲極電流

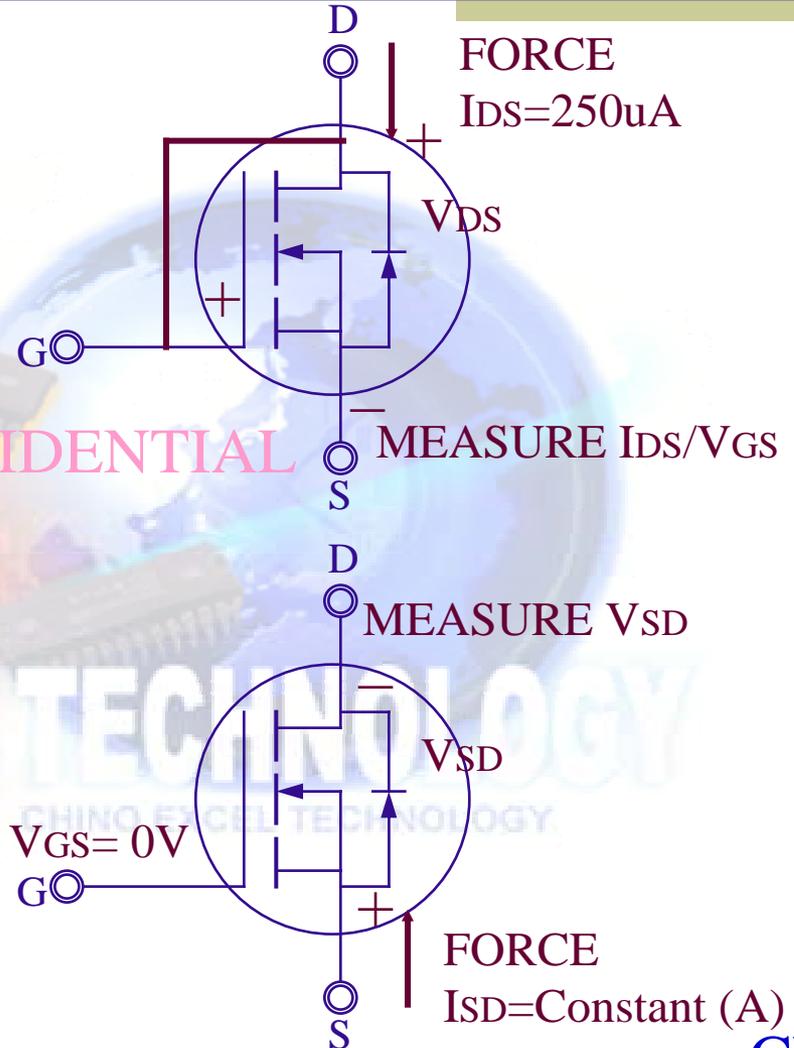


閘極--源極電壓V<sub>GS</sub>

## DC PARAMETER- $G_{FS}/V_{DS}$

$G_{FS}$ ：代表輸入與輸出的關係即 GATE 電壓變化, DRAIN 電流變化值, 單位為 S. 當汲極電流愈大,  $G_{FS}$  也會增大. 在切換動作的電路中,  $G_{FS}$  值愈高愈好.

$V_{FSD}$ : 此為二極體為順方向電流通時的電壓降.



# MOSFET 參數特性 - AC PARAMETER

## ❖ AC PARAMETER

### ➤ DYNAMIC CHARACTERISTICS

$C_{ISS}$  ,  $C_{OSS}$  ,  $C_{RSS}$

### ➤ GATE CHARGE

$Q_G$ / $Q_{GS}$ / $Q_{GD}$

### ➤ TURN-ON/OFF DELAY TIME

$T_d$  (ON) / $T_d$  (OFF)

### ➤ RISE / FALL TIME

$T_R$  / $T_F$

## AC PARAMETER - C<sub>ISS</sub> , C<sub>OSS</sub> ,C<sub>RSS</sub>

**C<sub>ISS</sub>** : 此為POWER MOS在截止狀態下的閘極輸入容量，為閘--源極間容量C<sub>GS</sub>與閘--汲極間容量C<sub>GD</sub>之和。特別是C<sub>GD</sub>為空乏層容量。其導通時的最大值，即是V<sub>DS</sub>=0V時。

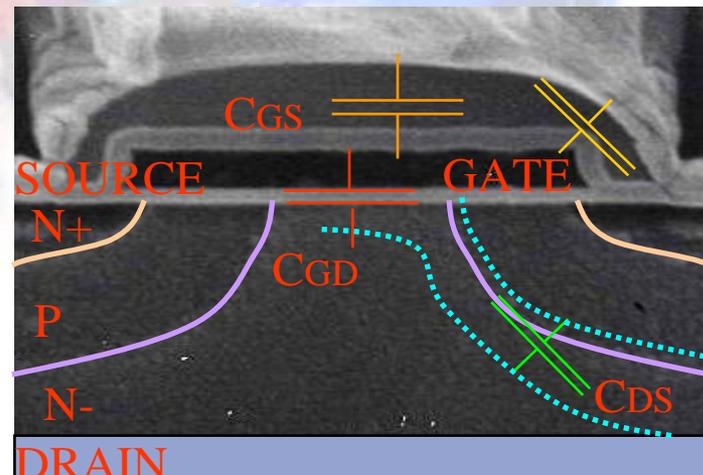
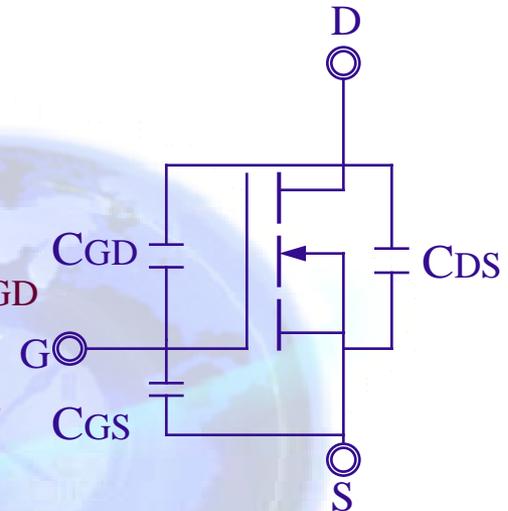
**C<sub>OSS</sub>** : 此為汲極--源極間的電容量，也可以說是內藏二極體在逆向偏壓時的容量。

**C<sub>RSS</sub>** : 此為汲極--閘極間的電容量，此對於高頻切換動作最有不良影響。為了提高元件高頻特性，C<sub>GD</sub>要愈低愈好。

$$C_{ISS} = C_{GS} + C_{GD}$$

$$C_{OSS} = C_{DS} + C_{GS} // C_{GD}$$

$$C_{RSS} = C_{GD}$$



## AC PARAMETER- (TD(ON/OFF)&T(RISE/FALL))

導通時間  $T_{ON}$  :

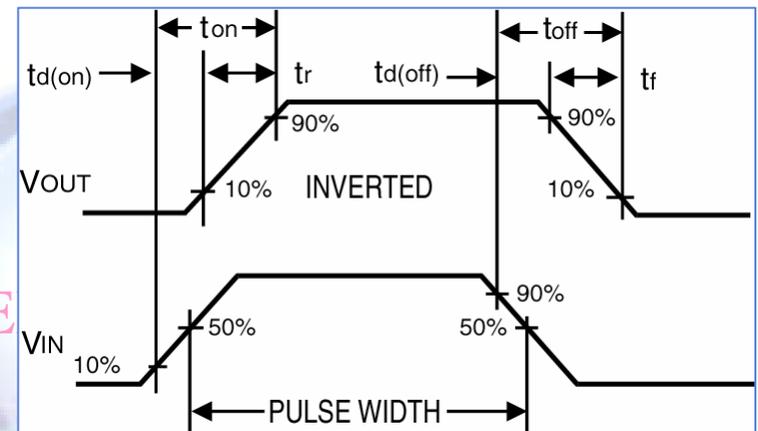
此為導通延遲時間 $T_D(ON)$ 與上升時間 $T_R$ 的和。由閘極電壓上昇至10%到 $V_{DS}$ 由於ON而下降至90%之值為止的時間，稱之為 $T_D(ON)$ ，而進一步至 $V_{DS}$ 成爲10%之值為止的時間稱之為 $T_R$ 。此一導通時間與閘極電壓以及信號源的阻抗有很大的關係，大致上成爲 $T_{ON}$  》

$R_G/V_GS$ 的關係。

截流時間  $T_{OFF}$  :

此為截流時間 $T_D(OFF)$ 與下降時間 $T_F$ 之和。由閘極電壓下降至90%開始，至 $V_{DS}$ 成爲OFF而上昇至10%之值為止的時間。稱之為 $T_D(OFF)$ ，更進一步至 $V_{DS}$ 上昇至90%為止的時間，稱之為 $T_F$ 。此一截流時間 $T_{OFF}$ 也與導通時間一樣與信號源阻抗及閘極電壓有很大關係。大致上可以用 $T_{OFF}$  》

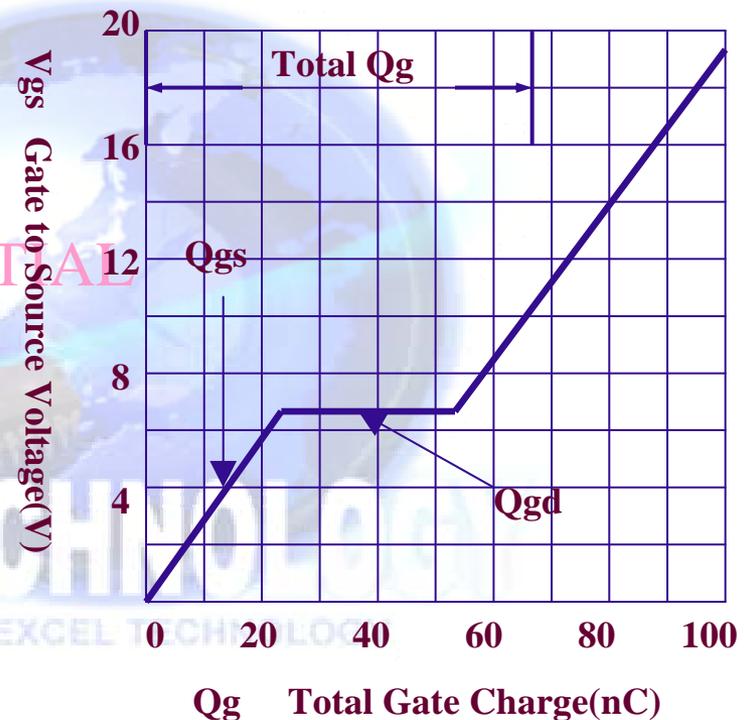
$R_G/V_GS$ 表示。



## AC PARAMETER - QG , QGS , QGD

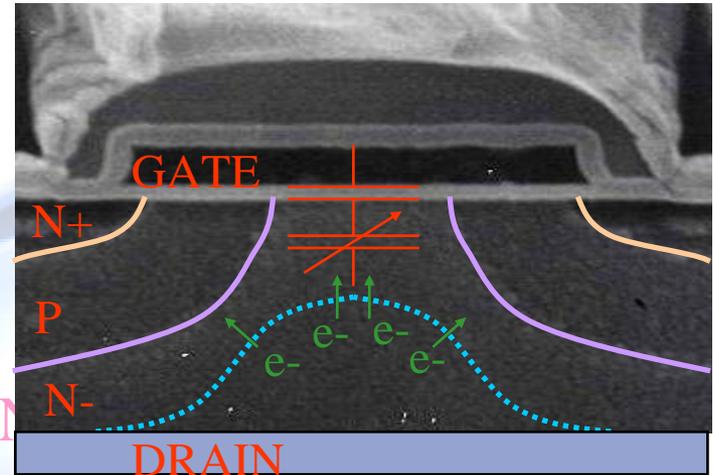
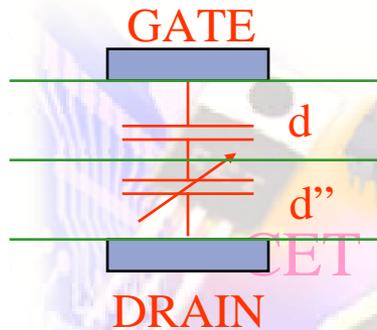
POWER MOS 的切換動作過程可以說是一種電荷移送現象。由於閘極完全是由絕緣膜覆蓋，其輸入阻抗幾乎是無限大，完全看輸入電容量的充電/放電動作來決定切換動作的狀態。

POWER MOS 在導通前可以分-- 啓閘值電壓之前/開始導通/完全導通三種狀態：  
啓閘值電壓：在電壓達到啓閘值電壓之前，輸入電容量幾乎是與閘極電容量 $C_{GS}$ 相等。在閘極正下方的汲極領域的空乏區會擴展，閘極- -汲極間的電容量與電極間距離有關。在導通的初期狀態，由於有 Miller 效應，輸入電容量的變化很複雜。當汲極電流愈增加時， $A_v$ 也會增加，Miller 效應會愈明顯。隨著汲極電流的增大，負載電阻的壓降也會增大，使加在 POWER MOS 的電壓下降。

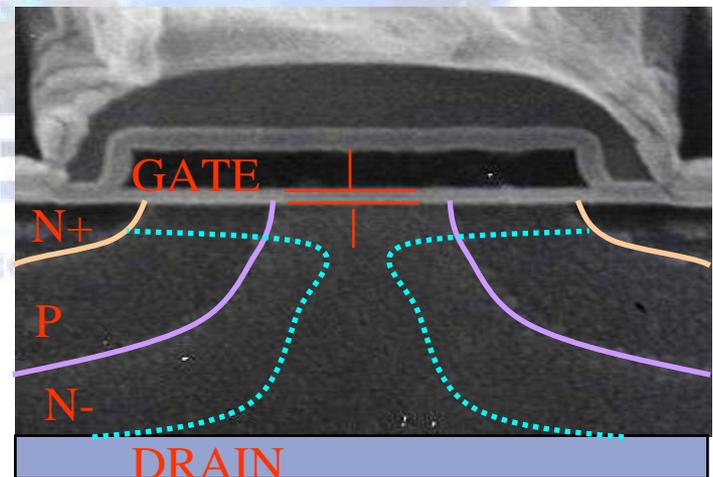
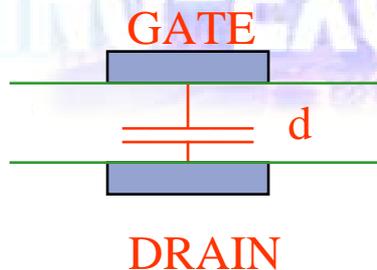


# AC PARAMETER - QG , QGS , QGD

開始導通：當所加的電壓 $V_{DS}$ 有變化時，空乏層的厚度 $d$ 也會發生變化。



完全導通：在完全導通時，輸入電容量可以視為 $C_{GD}$ 與 $C_{GS}$ 之和。



# MOSFET 參數特性 – POWER RELATED

## ❖ POWER RELATED

- POWER DISSIPATION
- CURRENT RATING
- MAXIMUM CURRENT RATING
- AVALANCHE

CHINO-EXCEL TECHNOLOGY

CHINO EXCEL TECHNOLOGY

# POWER RELATED-POWER DISSIPATION

PD: 為元件上所能承受電功率. 其運算式為:

$$PD(\max) = (T_J - T_C) / R_{\theta JC}$$

$$PD(\max) = (150^\circ\text{C} - 25^\circ\text{C}) / 2.1^\circ\text{C}/\text{W}$$
$$= 60\text{ W}$$

$T_J$  = 元件接合溫度.

$T_C$  = 外殼溫度.

$R_{\theta JC}$  = 晶片至外殼的熱電阻

CET CONFIDENTIAL

CHINO-EXCEL TECHNOLOGY

CHINO EXCEL TECHNOLOGY

# POWER RELATED-CURRENT RATING

$I_D$  : 為元件所能提供最大連續電流.

$I_D$  運算式:

$$I_D = \sqrt{[ P_D / R_{DSON}(MAX) ]}$$

$$I_D = \sqrt{[ 60W / 5 * 2.5 \Omega ]}$$

$$= 2A$$

$$*P_D = @T_J=150^{\circ}C$$

$$*R_{DSON}(MAX) = R(T) * R_{DSON}(MAX)$$

# MAXIMUM CURRENT RATING

$I_{DM}$  : 為元件所能承受瞬間最大電流.

$I_{DM}$ 運算法:

關於 $I_{DM}$ 值,該值乃是根據  $R_{DSON}$  – 溫度曲線圖和熱阻曲線 計算得知.

1.由SINGLE PULSE 300 $\mu$ S代入 FIGURE 得知  $R(T)$ 約等於 0.15.

$$\begin{aligned} 2. R_{\theta JC}(T) &= R_{\theta JC} * R(T) \\ &= 2.1^{\circ}\text{C}/\text{W} * 0.15 \\ &= 0.315^{\circ}\text{C}/\text{W} \end{aligned}$$

$$\begin{aligned} 3. P_{DM} &= (T_J - T_C) / R_{\theta JC}(T) \\ &= (150^{\circ}\text{C} - 25^{\circ}\text{C}) / 0.315^{\circ}\text{C}/\text{W} \\ &= 396^{\circ}\text{C}/\text{W}. \end{aligned}$$

$$\begin{aligned} 4. I_{DM} &= \sqrt{[P_{DM} / R_{DSON}(\text{max})]} \\ &= \sqrt{(396^{\circ}\text{C}/\text{W} / 10.5 \Omega)} \\ &= 6 \text{ A} . \end{aligned}$$

# MOSFET 參數特性 – POWER DISSIPATION

EAS AVALANCHE ENERGY 計算公式如下:

$$\begin{aligned} EAS &= 1/2 * L * I * I [V_{(BR)DSS} / (V_{(BR)DSS} - V_{DD})] \\ &= 1/2 * 60 \text{ mH} * 2 \text{ A} * 2 \text{ A} * [600 / (600 - 50)] \\ &= 120 \text{ mJ} \end{aligned}$$

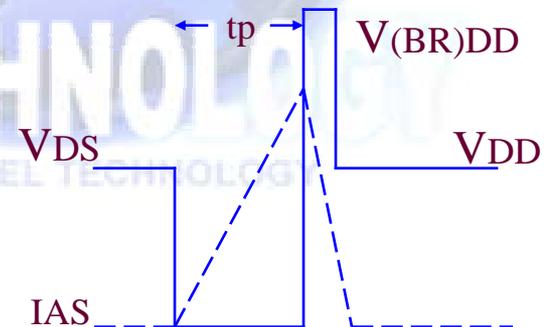
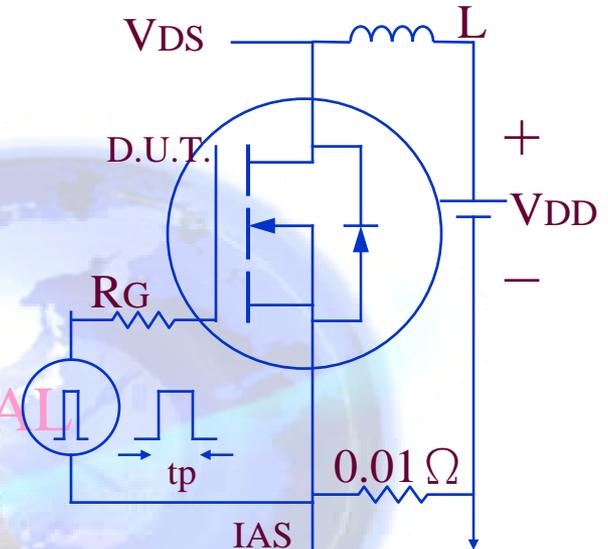
EAS=雪崩能量

L=電感值

I=電感峰值電流

BVDSS=雪崩擊穿電壓

VDD=電源電壓.



# MOSFET DATA SHEET - CEP(B)02N6



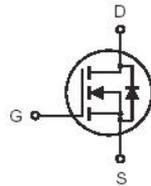
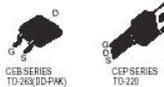
## CEP02N6/CEB02N6

Sep. 2002

### 4 N-Channel Logic Level Enhancement Mode Field Effect Transistor

#### FEATURES

- 600V, 2A,  $R_{DS(ON)}=5\Omega$  @ $V_{GS}=10V$ .
- Super high dense cell design for extremely low  $R_{DS(ON)}$ .
- High power and current handling capability.
- TO-220 & TO-263 package.



#### ABSOLUTE MAXIMUM RATINGS (Tc=25°C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V <sub>DS</sub>	600	V
Gate-Source Voltage	V <sub>GS</sub>	±30	V
Drain Current-Continuous - Pulsed	I <sub>D</sub>	2	A
	I <sub>DM</sub>	6	A
Drain-Source Diode Forward Current	I <sub>S</sub>	6	A
Maximum Power Dissipation @Tc=25°C Derate above 25°C	P <sub>D</sub>	60	W
		0.48	W/°C
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	°C

#### THERMAL CHARACTERISTICS

Thermal Resistance, Junction-to-Case	R <sub>θJC</sub>	2.1	°C/W
Thermal Resistance, Junction-to-Ambient	R <sub>θJA</sub>	62.5	°C/W

4-2

## CEP02N6/CEB02N6

### ELECTRICAL CHARACTERISTICS (Tc=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>DRAIN-SOURCE AVALANCHE RATING<sup>a</sup></b>						
Single Pulse Avalanche Energy <sup>c</sup>	E <sub>AS</sub>			125		mJ
Avalanche Current	I <sub>AR</sub>			2		A
Repetitive Avalanche Energy	E <sub>AR</sub>			5.4		mJ
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	600			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 600V, V <sub>GS</sub> = 0V			25	μA
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = ±30V, V <sub>DS</sub> = 0V			±100	nA
<b>ON CHARACTERISTICS<sup>a</sup></b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>GS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	2		4	V
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 1A		3.8	5.0	Ω
On-State Drain Current	I <sub>D(ON)</sub>	V <sub>GS</sub> = 10V, V <sub>DS</sub> = 10V	2			A
Forward Transconductance	g <sub>FS</sub>	V <sub>GS</sub> = 50V, I <sub>D</sub> = 1A		1.2		S
<b>SWITCHING CHARACTERISTICS<sup>b</sup></b>						
Turn-On Delay Time	t <sub>D(ON)</sub>	V <sub>DS</sub> = 300V, I <sub>D</sub> = 2A, V <sub>GS</sub> = 10V R <sub>CE(ON)</sub> = 18Ω		18	35	ns
Rise Time	t <sub>r</sub>			18	35	ns
Turn-Off Delay Time	t <sub>D(OFF)</sub>			50	90	ns
Fall Time	t <sub>f</sub>			16	40	ns
Total Gate Charge	Q <sub>g</sub>	V <sub>GS</sub> = 480V, I <sub>D</sub> = 2A, V <sub>DS</sub> = 10V		20	25	nC
Gate-Source Charge	Q <sub>gs</sub>			2		nC
Gate-Drain Charge	Q <sub>gd</sub>			12		nC

4-3

# MOSFET DATA SHEET - CEP(B)02N6

## CEP02N6/CEB02N6

4

### ELECTRICAL CHARACTERISTICS (T<sub>c</sub>=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>DYNAMIC CHARACTERISTICS<sup>b</sup></b>						
Input Capacitance	C <sub>iss</sub>	V <sub>ds</sub> = 25V, V <sub>gs</sub> = 0V f = 1.0MHz		250		pF
Output Capacitance	C <sub>oss</sub>			50		pF
Reverse Transfer Capacitance	C <sub>rss</sub>			30		pF
<b>DRAIN-SOURCE DIODE CHARACTERISTICS<sup>a</sup></b>						
Diode Forward Voltage	V <sub>sd</sub>	V <sub>gs</sub> = 0V, I <sub>s</sub> = 2A		1.5		V

#### Notes

- a. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.  
b. Guaranteed by design, not subject to production testing.  
c. L = 60mH, I<sub>AS</sub> = 2.0A, V<sub>DD</sub> = 50V, R<sub>θ</sub> = 25°C

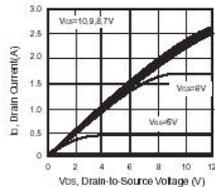


Figure 1. Output Characteristics

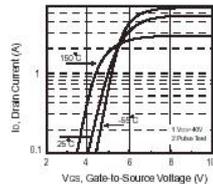


Figure 2. Transfer Characteristics

4-4

## CEP02N6/CEB02N6

4

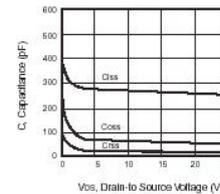


Figure 3. Capacitance

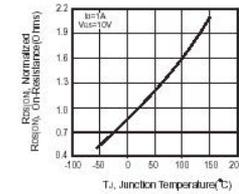


Figure 4. On-Resistance Variation with Temperature

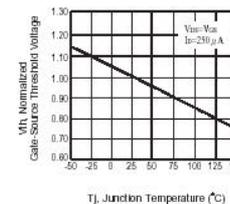


Figure 5. Gate Threshold Variation with Temperature

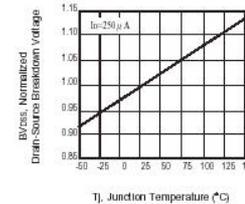


Figure 6. Breakdown Voltage Variation with Temperature

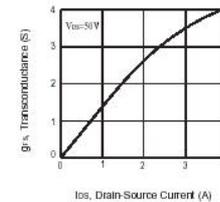


Figure 7. Transconductance Variation with Drain Current

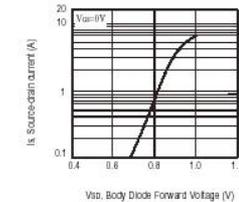


Figure 8. Body Diode Forward Voltage Variation with Source Current

4-5

# MOSFET DATA SHEET - CEP(B)02N6

## CEP02N6/CEB02N6

4

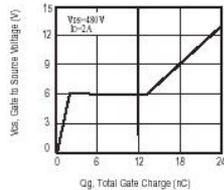


Figure 9. Gate Charge

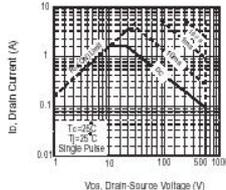


Figure 10. Maximum Safe Operating Area

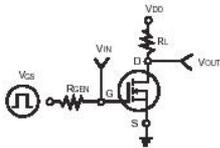


Figure 11. Switching Test Circuit

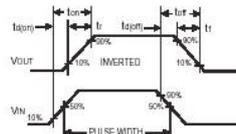


Figure 12. Switching Waveforms

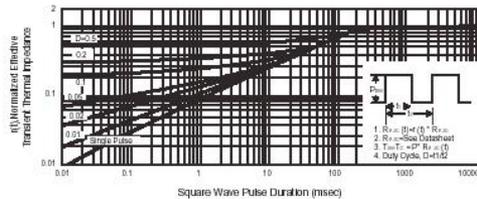


Figure 13. Normalized Thermal Transient Impedance Curve

